

# SVD aDefectFinder

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# Introduction

- SVD aDefectFinder is a package to analyze the full local run data.
- It identifies the following defects.
  - Short
  - Open
  - Pinhole
  - Noisy strip
- In this study the test is performed on the local run data from 21/02/2024 and compared with the analyzed data from 2/06/2023

# Classification criteria

## [P-side selection criteria]

Noise > 8

CalAmp < 60 || CalAmp > 130

CalTmax < 30 || CalTmax > 80

ParticleResponse < 0.50

is-a-pinhole criteria

## [P-side classification criteria]

Pinhole: 1)  $\text{abs}(\text{average\_R} - \text{max\_C}) > 20.0$

2)  $\text{abs}(\text{average\_L} - \text{max\_C}) > 20.0$

normal: 1) and 2)

Short:  $\text{average}(\text{Mean}) < 50.0$

Open: - Noise > 25 && Noise > 8 for the adjacent strips

-  $\text{CalTmax} < \text{Mean}(\text{CalTmax})_{\text{chip}} - 3 * \text{RMS}(\text{CalTmax})_{\text{chip}}$

## [N-side selection criteria]

Noise > 8

CalAmp < 60 || CalAmp > 130

CalTmax < 30 || CalTmax > 80

ParticleResponse < 0.50

is-a-pinhole criteria

## [N-side classification criteria]

Pinholes: 1)  $\text{abs}(\text{average\_R} - \text{max\_C}) > 20.0$

2)  $\text{abs}(\text{average\_L} - \text{max\_C}) > 20.0$

normal: 1) and 2)

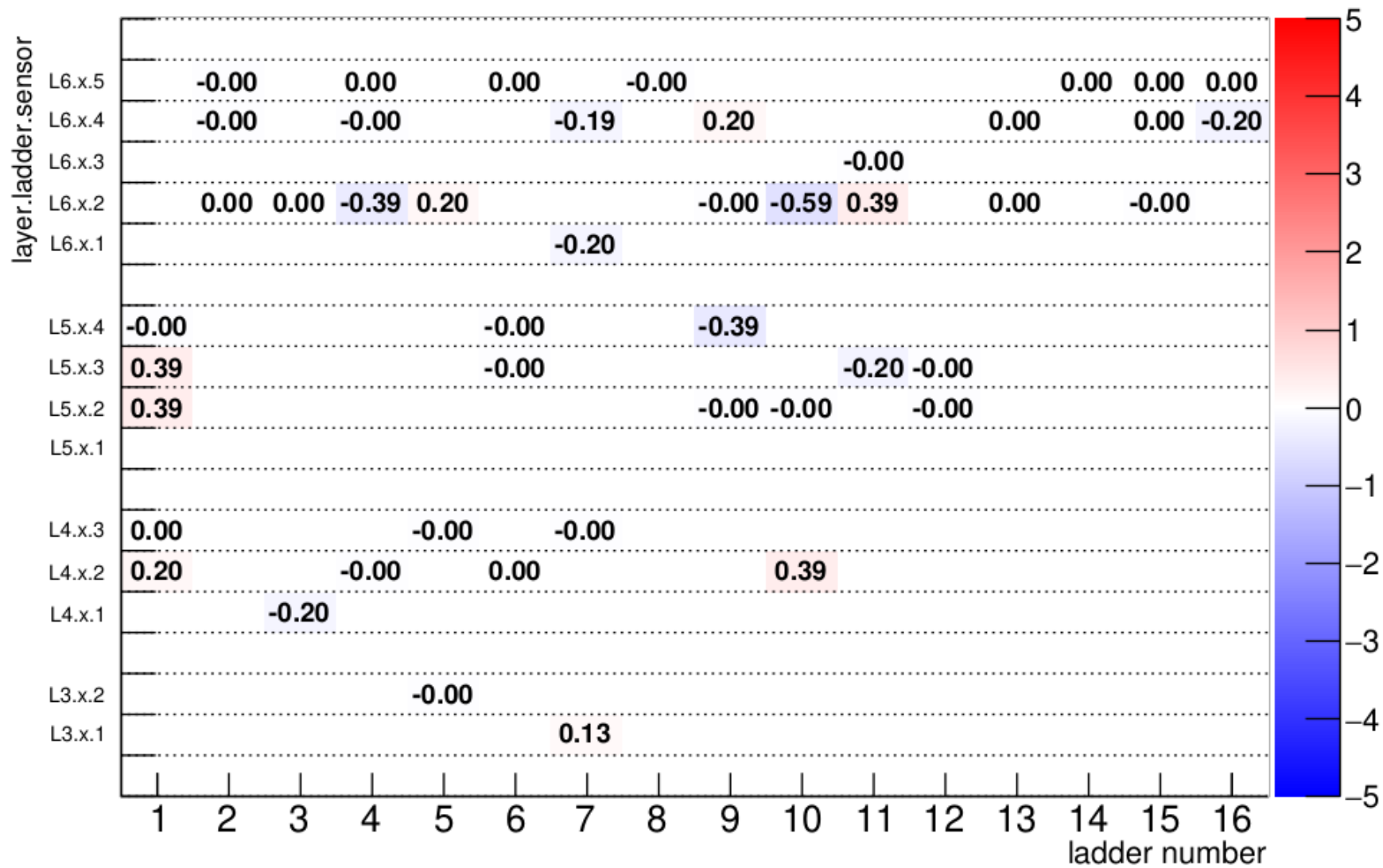
Short:  $\text{average}(\text{Mean}) < 50.0$

Open: - Noise > 25 && Noise > 8 for the adjacent strips

-  $\text{CalTmax} < \text{Mean}(\text{CalTmax})_{\text{chip}} - 3 * \text{RMS}(\text{CalTmax})_{\text{chip}}$



TOT\_Defects/N\_Strips (%) of defects in each sensor, V side







# Comparison

- After identifying the pinholes, checked the details in the pdf files generated.
- As per details in the summary files, two fake pinholes were mentioned.
- While others were also reported in the individual pdf summary files.
- Also compared with the pdf's of the previous calibration (02/06/2023) and there were 5/23 pdf with exactly same number of pinholes in the P and N sides while others were having different number of pinholes in the P and N sides.



# Pdf files summary examples

## L3.7.2

### P-side

number of defects = 1 / 768 (0.13%)

# p\_Noisy = 0 (0.00%)

# p\_Open = 0 (0.00%)

# p\_Short = 1 (0.13%)

# p\_Pinhole = 0 (0.00%)

# p\_Particle\_Resp = 0 (0.00%)

### N-side

number of defects = 1 / 768 (0.13%)

# n\_Noisy = 0 (0.00%)

# n\_Open = 0 (0.00%)

# n\_Short = 0 (0.00%)

# n\_Pinhole = 1 (0.13%)

# n\_Particle\_Resp = 0 (0.00%)

## L6.10.2

### P-side

number of defects = 13 / 768 (1.69%)

# p\_Noisy = 7 (0.91%)

# p\_Open = 1 (0.13%)

# p\_Short = 0 (0.00%)

# p\_Pinhole = 5 (0.65%)

# p\_Particle\_Resp = 0 (0.00%)

### N-side

number of defects = 6 / 512 (1.17%)

# n\_Noisy = 1 (0.20%)

# n\_Open = 5 (0.98%)

# n\_Short = 0 (0.00%)

# n\_Pinhole = 0 (0.00%)

# n\_Particle\_Resp = 0 (0.00%)

# Summary

- Understood all the procedure and tested on two different data.
- Still a lot to understand in analysis of the data produced after the tests (As per initial investigation 23 pinholes are found which seems quite a big number).
- Planning to present it in the next SVD meeting.

Backup

# List of the defective strips

```
N L6.2.5 -1.0
P L6.12.5 -1.0
N L6.12.5 -1.0
P L6.14.4 -1.01
P L6.3.3 -1.01
P L6.4.3 -1.0
N L6.4.3 -1.0
P L6.12.3 -2.99
P L6.5.2 1.0
N L6.5.2 1.0
P L6.16.2 -0.99
P L6.8.1 1.0
N L6.8.1 1.0
P L5.8.3 0.99
P L5.12.1 -1.0
P L4.9.3 -1.0
P L4.4.1 3.0
N L4.4.1 3.0
P L4.5.1 4.0
N L4.5.1 4.0
N L4.9.1 -1.0
N L3.7.2 -1
P L6.7.3 0.99
P L6.8.4 -1.0
P L6.16.4 2.0
P L6.10.2 -1.02
P L5.1.3 1.0
N L5.1.3 1.0
P L5.1.2 -1
P L4.10.2 1.0
N L4.10.2 1.0
```